

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination HUI ET AL.	
		Examiner Khiem D Nguyen	Art Unit 2823	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,313,043	11-2001	Hattori, Atsuo	438/745
*	B	US-6,376,303	04-2002	Seo et al.	438/253
*	C	US-6,548,408	04-2003	Morgan, Rod	438/692
*	D	US-6,646,314	11-2003	Rudhard, Joachim	257/415
*	E	US-6,743,728	06-2004	Ho et al.	438/700
*	F	US-2002/0125521	09-2002	Schrems, Martin	257/301
*	G	US-2004/0058549	03-2004	Ho et al.	438/694
*	H	US-2002/0168834	11-2002	Chen et al.	438/427
*	I	US-2002/0163026	11-2002	Park, Hong-Bae	257/301
*	J	US-2002/0004281	01-2002	Lee et al.	438/424
*	K	US-2001/0001723	05-2001	GARDNER et al.	438/305
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.